

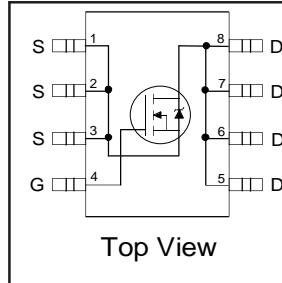
HEXFET® Power MOSFET

- Generation V Technology
- Ultra Low On-Resistance
- N-Channel Mosfet
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching
- 100% R_G Tested

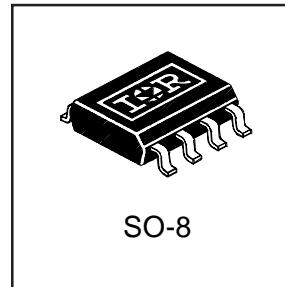
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques. Power dissipation of greater than 0.8W is possible in a typical PCB mount application.



$V_{DSS} = 30V$
 $R_{DS(on)} = 0.011\Omega$



Absolute Maximum Ratings

Symbol	Parameter	Max	Units
V_{DS}	Drain-to-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	13	
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	9.2	A
I_{DM}	Pulsed Drain Current ①	58	
$P_D @ T_A = 25^\circ C$	Power Dissipation	2.5	W
	Linear Derating Factor	0.02	mW/°C
E_{AS}	Single Pulse Avalanche Energy ②	260	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150	°C

Thermal Resistance Ratings

Symbol	Parameter	Typ	Max	Units
R_{0JL}	Junction-to-Drain Lead ④	—	20	
R_{0JA}	Junction-to-Ambient ⑤⑥	—	50	°C/W

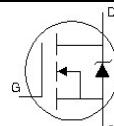
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Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	30	—	—	V	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.034	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.011	Ω	$V_{GS} = 10\text{V}$, $I_D = 7.3\text{A}$ ④
		—	—	0.018		$V_{GS} = 4.5\text{V}$, $I_D = 3.7\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	1.0	—	3.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	10	—	—	S	$V_{DS} = 10\text{V}$, $I_D = 3.7\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{DS} = 30\text{V}$, $V_{GS} = 0\text{V}$
		—	—	25		$V_{DS} = 24\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	$V_{GS} = -20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	100		$V_{GS} = 20\text{V}$
Q_g	Total Gate Charge	—	52	79	nC	$I_D = 7.3\text{A}$
Q_{gs}	Gate-to-Source Charge	—	6.1	9.2		$V_{DS} = 24\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	16	23		$V_{GS} = 10\text{V}$, See Fig. 6 and 9 ④
R_G	Gate Resistance	1.2	—	3.7		
$t_{d(on)}$	Turn-On Delay Time	—	8.6	—	ns	$V_{DD} = 15\text{V}$
t_r	Rise Time	—	50	—		$I_D = 7.3\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	52	—		$R_G = 6.2 \Omega$
t_f	Fall Time	—	46	—		$R_G = 2.0\Omega$, See Fig. 10 ④
C_{iss}	Input Capacitance	—	1800	—	pF	$V_{GS} = 0\text{V}$
C_{oss}	Output Capacitance	—	680	—		$V_{DS} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	240	—		$f = 1.0\text{MHz}$, See Fig. 5

Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	3.1	A	MOSFET symbol showing the integral reverse p-n junction diode.
	Pulsed Source Current (Body Diode) ①	—	—	58		
	Diode Forward Voltage	—	—	1.0		$T_J = 25^\circ\text{C}$, $I_S = 7.3\text{A}$, $V_{GS} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	74	110	ns	$T_J = 25^\circ\text{C}$, $I_F = 7.3\text{A}$
Q_{rr}	Reverse Recovery Charge	—	200	300	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

③ $I_{SD} \leq 7.3\text{A}$, $dI/dt \leq 100\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 150^\circ\text{C}$

② Starting $T_J = 25^\circ\text{C}$, $L = 9.8\text{mH}$
 $R_G = 25\Omega$, $I_{AS} = 7.3\text{A}$. (See Figure 12)

④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.

⑤ Surface mounted on FR-4 board

⑥ R_θ is measured at T_J approximately 90°C

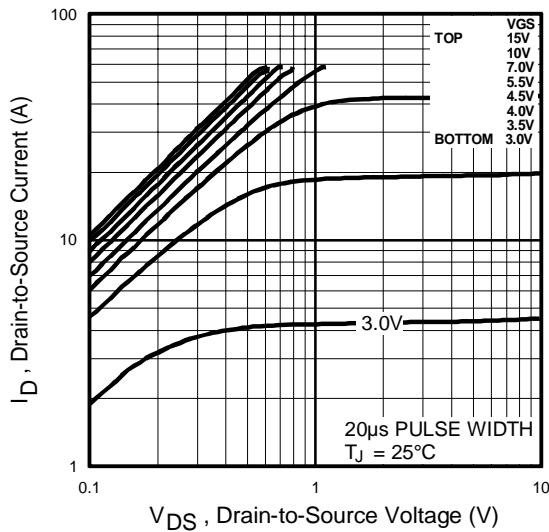


Fig 1. Typical Output Characteristics

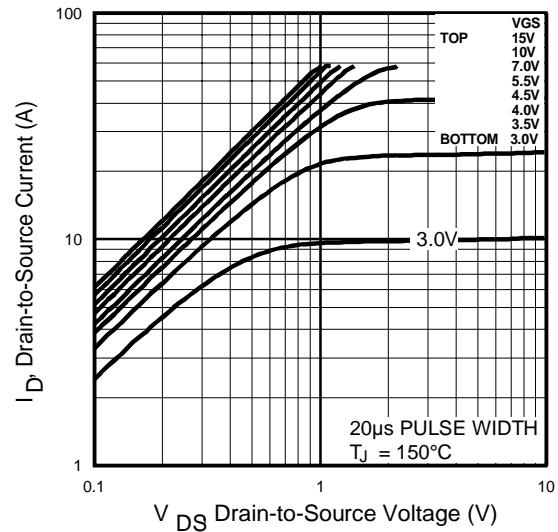


Fig 2. Typical Output Characteristics

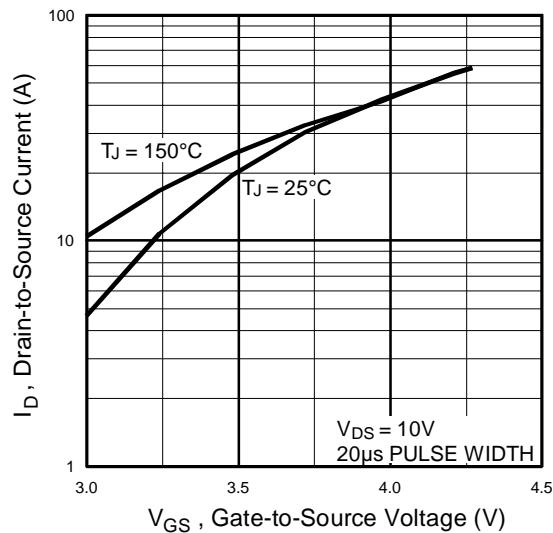


Fig 3. Typical Transfer Characteristics

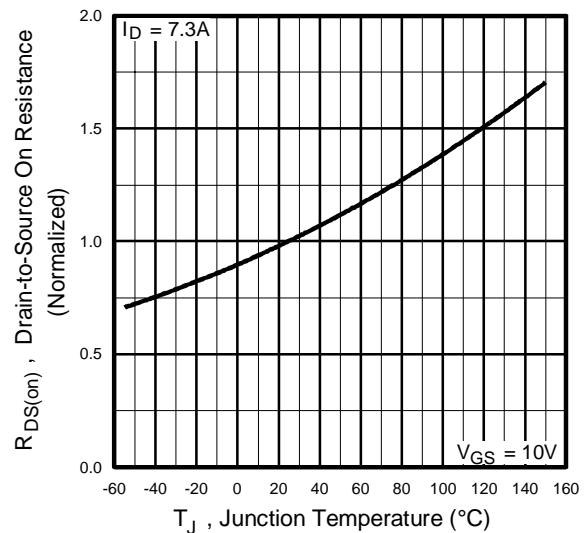


Fig 4. Normalized On-Resistance
Vs. Temperature

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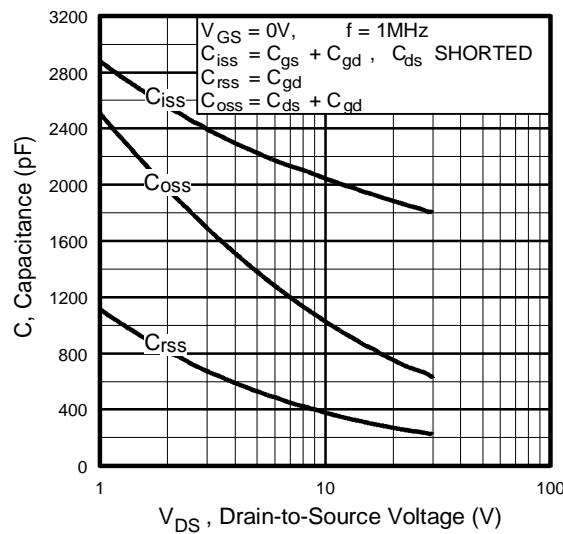


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

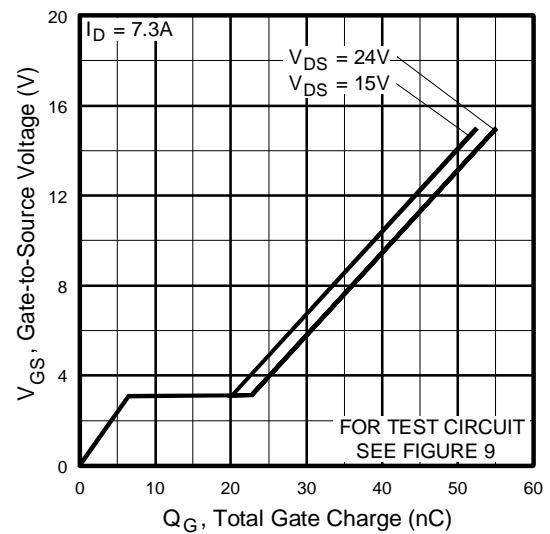


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

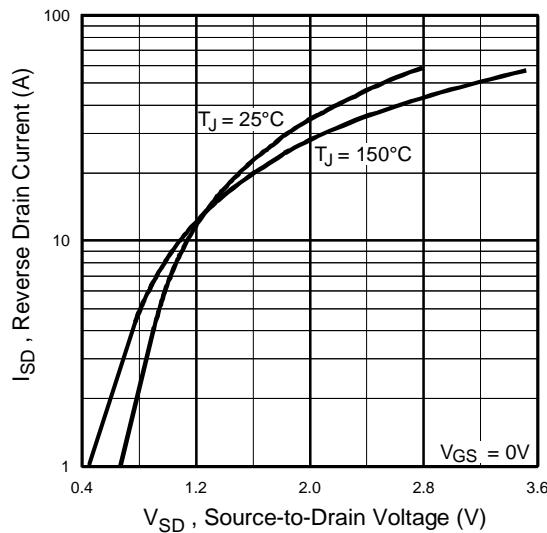


Fig 7. Typical Source-Drain Diode
Forward Voltage

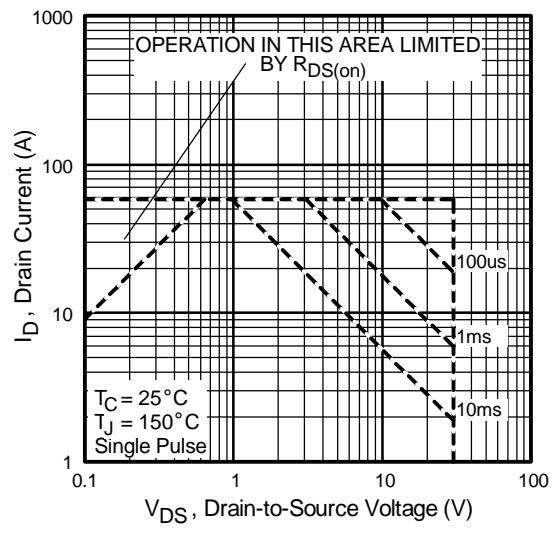


Fig 8. Maximum Safe Operating Area

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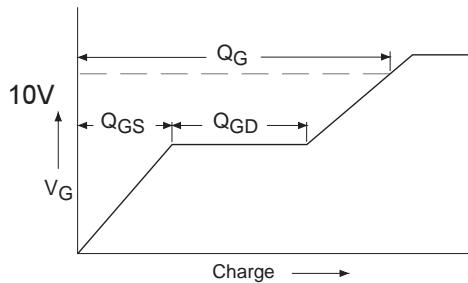


Fig 9a. Basic Gate Charge Waveform

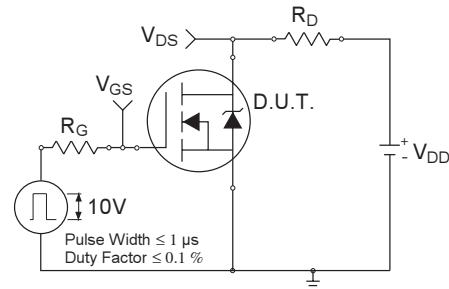


Fig 10a. Switching Time Test Circuit

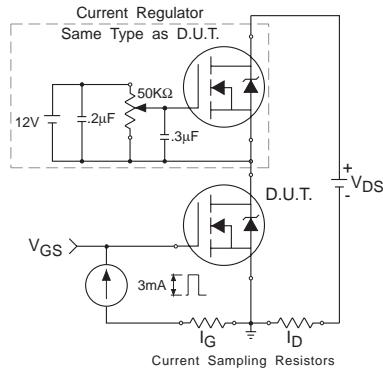


Fig 9b. Gate Charge Test Circuit

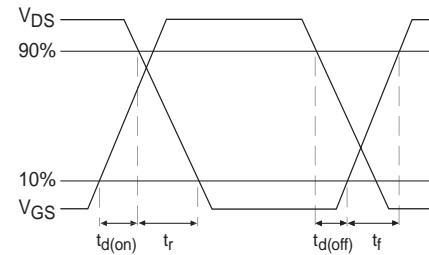


Fig 10b. Switching Time Waveforms

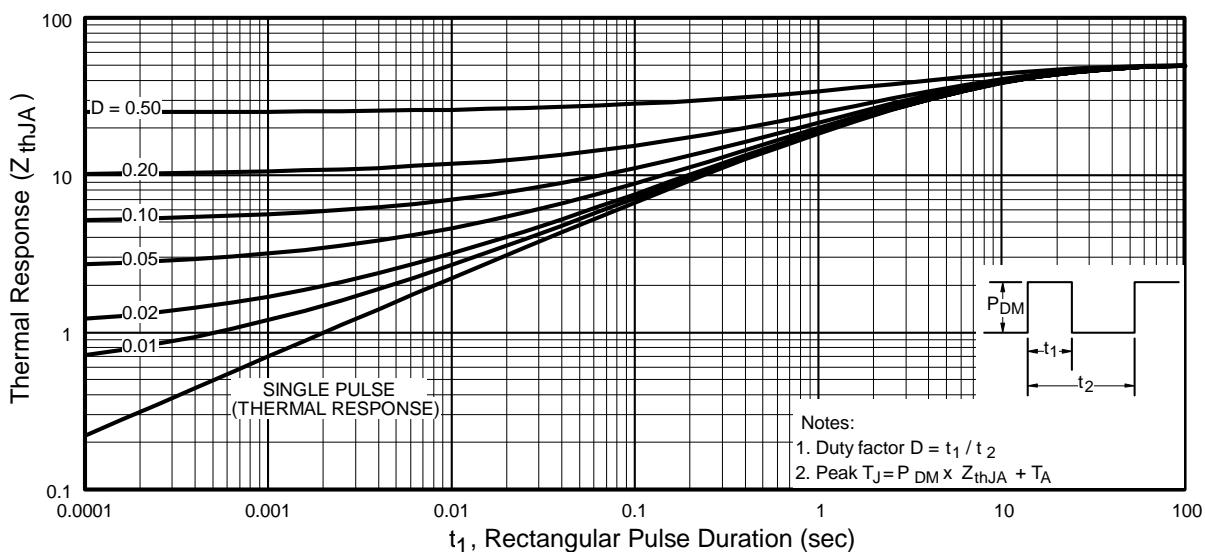


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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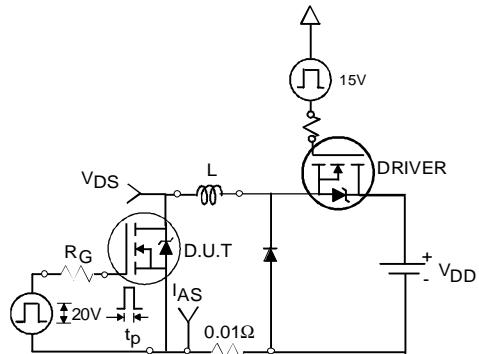


Fig 12a. Unclamped Inductive Test Circuit

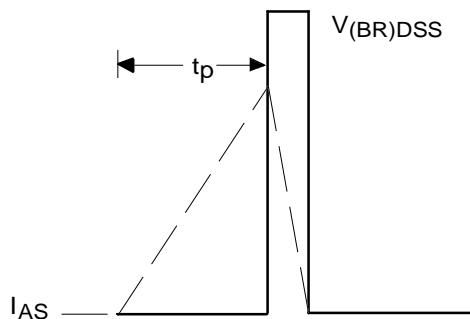


Fig 12b. Unclamped Inductive Waveforms

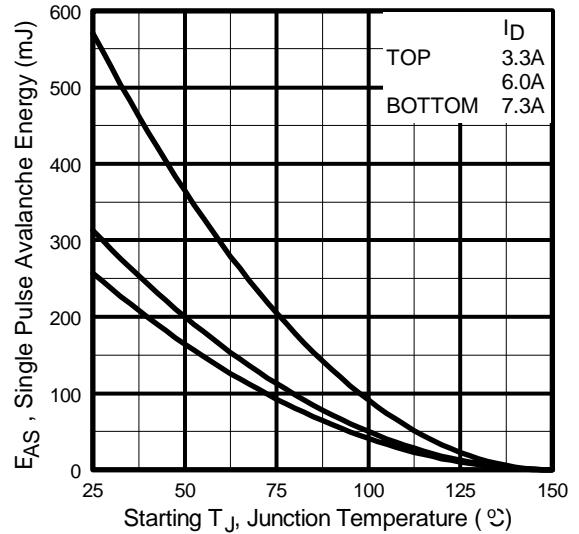


Fig 12c. Maximum Avalanche Energy
Vs. Drain Current

Peak Diode Recovery dv/dt Test Circuit

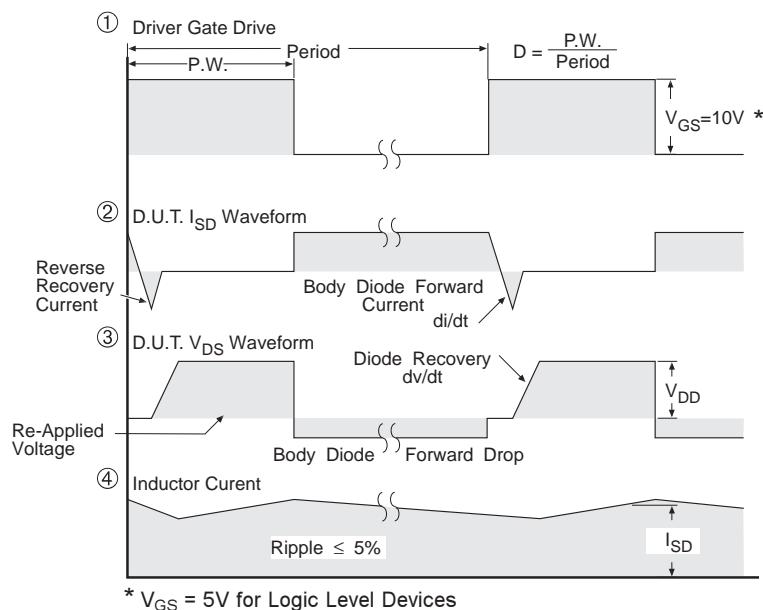
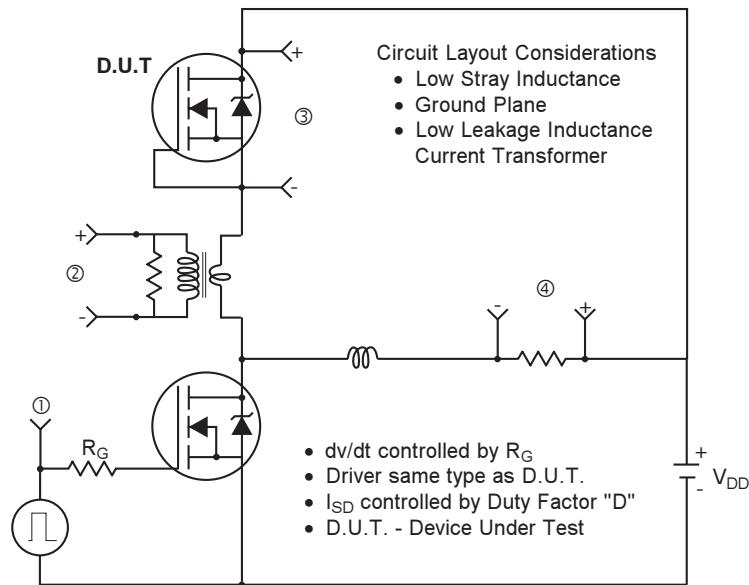
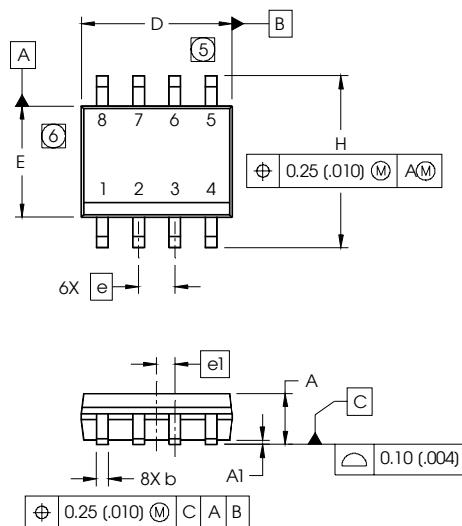


Fig 13. For N-Channel HEXFETs

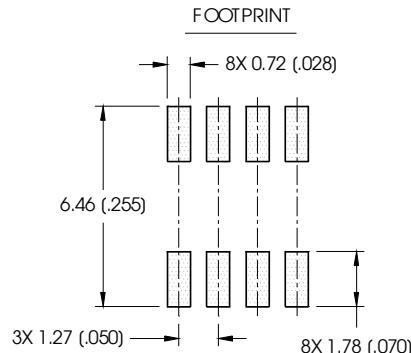
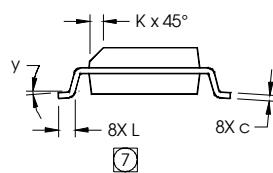
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SO-8 Package Details

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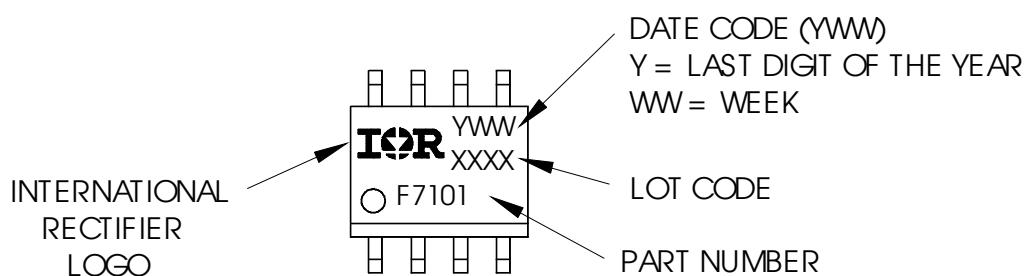


DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



SO-8 Part Marking

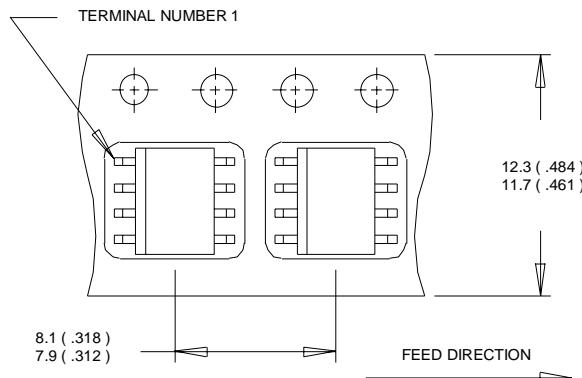
EXAMPLE: THIS IS AN IRF7101 (MOSFET)



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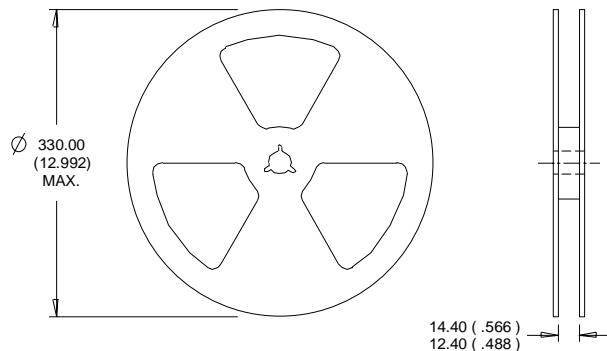
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SO-8 Tape and Reel



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

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